

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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		Examiner	Art Unit	Page 1 of 1
		Romain Jeanty	3624	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,409,357	08-2008	Schaf et al.	705/7
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Feather et al (Combining the best attributes of qualitative and quantitative riskmanagement tool support), 12/2000, IEEE, Pages 309-312
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	X	Alexander Carol (Bayesian Methods for Measuring Operational Risk Discussion Papers in Finance 2000-02, ISMA Centre, Pages 1-22

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.